Project 4 Algorithm Implementation

Group 3

Outline

- Error Detection Using SVM
 - Feature Extraction
 - Model Tuning
- Error Correction with Binary N-grams
- Evaluation and Performance

Project Objective

- Optical Character Recognition (OCR) software is widely available in proprietary (AbbyReader) and open-source (Google Tesseract) form
 - Performance is often disappointing even with additional training
 - Experience with Columbia's <u>HistoryLab</u>
- Given a set of poorly OCR'ed documents and their ground truth pairs, can we improve the detection and correction of incorrect terms?
 - Detection using SVM (paper D3)
 - Correction using Binary N-grams (C1)

Recognizing Garbage in OCR Output on Historical Documents

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- Feature Extraction based on series of rules
 - Length of token, ratio of vowels to consonants, ...
- Unique Bigram Frequency feature
 - Attempt to capture the likelihood of two characters appearing together
 - 'ed' vs. 'yy'



Figure 1: Images and OCR result aligned showing garbage and non-garbage tokens.

- Feature rules were developed with historical German texts in mind,
 - Higher likelihood of non-alphanumeric characters
- Some features related to
 non-alphanumeric characters were
 dropped at model fitting due to constant
 values



Figure 1: Images and OCR result aligned showing garbage and non-garbage tokens.

- Model fit using LIBSVM implementation in e1071 package
 - radial kernel
 - Training set of 75%, test set 25%
- Hyperparameter Tuning (gamma and cost)
 - Grid search implementation
 - Runtime considerations
 - Bayesian Optimization
 - Search over posterior distribution of functions
- Ultimate detection rate of ~80%

Error Correction

A Contextual Postprocessing System for Error Correction Using Binary n-Grams

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Performance and Evaluation